





### 100V P-CHANNEL ENHANCEMENT MODE MOSFET

#### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub> T <sub>A</sub> = 25°C
-100V	350mΩ @ V <sub>GS</sub> = -10V	-1.6
	450mΩ @ V <sub>GS</sub> = -6.0V	-1.4

### **Description and Applications**

This MOSFET has been designed to minimize the on-state resistance and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Motor control
- DC-DC Converters
- Power management functions
- Uninterrupted power supply

#### **Features and Benefits**

- · Fast switching speed
- Low gate drive
- Low input capacitance
- Qualified to AEC-Q101 Standards for High Reliability

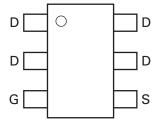
#### **Mechanical Data**

- Case: SOT23-6
- Case Material: Molded Plastic, UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin annealed over Copper lead frame.
   Solderable per MIL-STD-202, Method 208
- Weight: 0.018 grams (approximate)

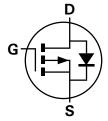
#### SOT23-6



Top View



Pin Out - Top View

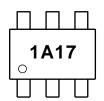


Equivalent Circuit

### **Ordering Information**

Product	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMP10A17E6TA	See below	7	8	3,000

# **Marking Information**



1A17 = Product Type Marking Code





#### **Maximum Ratings** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source voltage			$V_{DSS}$	-100	V
Gate-Source voltage			$V_{GS}$	±20	V
		(Note 2)		-1.6	
Continuous Drain current	$V_{GS} = 10V$	$T_A = 70$ °C (Note 2)	I <sub>D</sub>	-1.3	Α
		(Note 1)		-1.3	
Pulsed Drain current	V <sub>GS</sub> = 10V	(Note 3)	I <sub>DM</sub>	-7.7	Α
Continuous Source current (	Body diode)	(Note 2)	I <sub>S</sub>	-2.1	Α
Pulsed Source current (Body diode) (Note3)		I <sub>SM</sub>	-7.7	Α	

### Thermal Characteristics @TA = 25°C unless otherwise specified

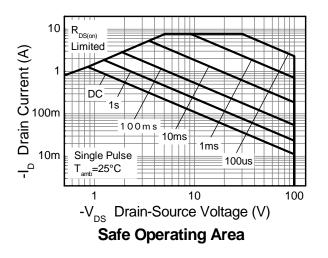
Characteristic		Symbol	Value	Unit	
Power dissipation	(Note 1)	9	1.1 8.8	W mW/°C	
Linear derating factor	(Note 2)	P <sub>D</sub>	1.7 13.7		
Thermal Resistance, Junction to Ambient	(Note 1)		113	°C/W	
	(Note 2)	$R_{\theta JA}$	73		
Operating and storage temperature range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C	

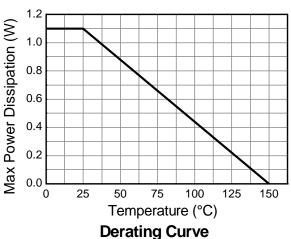
Notes:

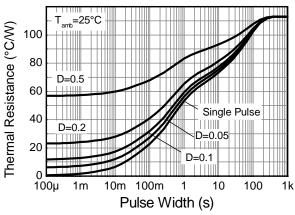
- 1. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 2. Same as note (1), except the device is measured at  $t \le 5$  sec.
- 3. Same as note (1), except the device is pulsed with D= 0.02 and pulse width 300 µs. The pulse current is limited by the maximum junction temperature.

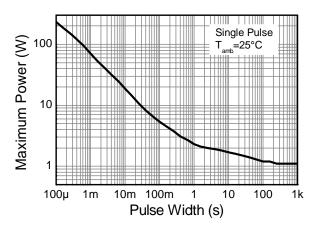


# **Thermal Characteristics**









**Transient Thermal Impedance** 

**Pulse Power Dissipation** 





# Electrical Characteristics @T<sub>A</sub> = 25°C unless otherwise specified

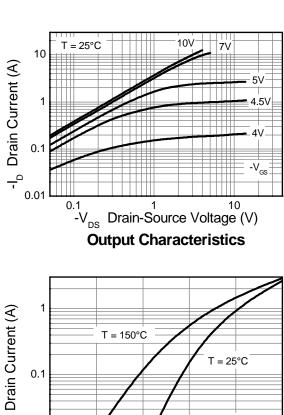
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-100	_	_	V	$I_D = -250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-0.5	μА	V <sub>DS</sub> = -100V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V$ , $V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(th)}$	-2.0	_	-4.0	V	$I_D$ = -250 $\mu$ A, $V_{DS}$ = $V_{GS}$	
Static Drain-Source On-Resistance (Note 4)	D	ı		0.350	Ω	$V_{GS}$ = -10V, $I_{D}$ = -1.4A	
Static Drain-Source Off-Resistance (Note 4)	R <sub>DS</sub> (ON)			0.450	\$2	V <sub>GS</sub> = -6V, I <sub>D</sub> = -1.2A	
Forward Transconductance (Notes 4 & 5)	g <sub>fs</sub>	_	2.8	_	S	V <sub>DS</sub> = -15V, I <sub>D</sub> = -1.4A	
Diode Forward Voltage (Note 4)	$V_{SD}$		-0.85	-0.95	V	I <sub>S</sub> = -1.7A, V <sub>GS</sub> = 0V	
Reverse recovery time (Note 5)	t <sub>rr</sub>		33	_	ns	-I <sub>S</sub> = -1.5A, di/dt= 100A/μs	
Reverse recovery charge (Note 5)	Qrr		48	_	nC		
DYNAMIC CHARACTERISTICS (Note 5)							
Input Capacitance	C <sub>iss</sub>		424	_	pF	V <sub>DS</sub> = -50V, V <sub>GS</sub> = 0V -f= 1MHz	
Output Capacitance	Coss		36.6	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>		29.8	_	pF	1- 1101112	
Total Gate Charge (Note 6)	$Q_g$		7.1	_	nC	V <sub>GS</sub> = -6.0V	
Total Gate Charge (Note 6)	$Q_g$	_	10.7	_	nC	V <sub>DS</sub> = -50V	
Gate-Source Charge (Note 6)	$Q_{gs}$	_	1.7	_	nC	V <sub>GS</sub> = -10V	
Gate-Drain Charge (Note 6)	$Q_{gd}$	_	3.8	_	nC		
Turn-On Delay Time (Note 6)	t <sub>D(on)</sub>	_	3.0	_	ns		
Turn-On Rise Time (Note 6)	t <sub>r</sub>	_	3.5		ns	$V_{DD}$ = -50V, $V_{GS}$ = -10V $I_{D}$ = -1A, $R_{G} \cong 6.0\Omega$	
Turn-Off Delay Time (Note 6)	t <sub>D(off)</sub>	_	13.4	_	ns		
Turn-Off Fall Time (Note 6)	t <sub>f</sub>		7.2		ns		

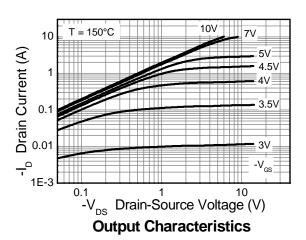
Notes:

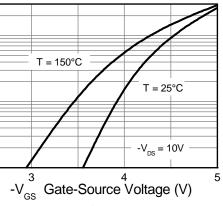
- 4. Measured under pulsed conditions. Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$
- 5. For design aid only, not subject to production testing.
  6. Switching characteristics are independent of operating junction temperatures.

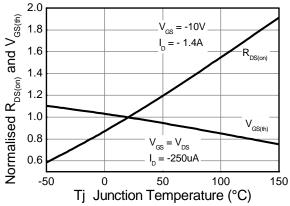


## **Typical Characteristics**



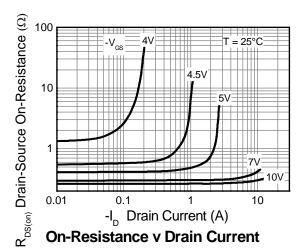


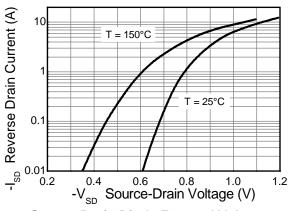




**Typical Transfer Characteristics** 



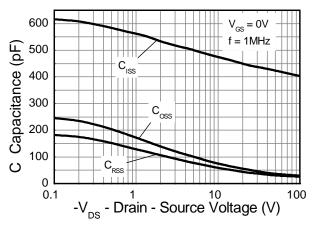




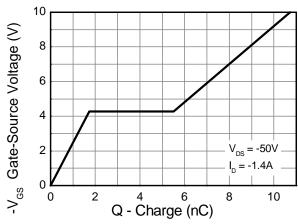
**Source-Drain Diode Forward Voltage** 



## **Typical Characteristics - continued**

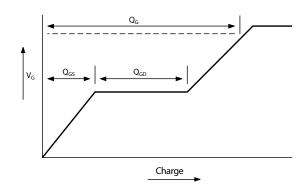


Capacitance v Drain-Source Voltage

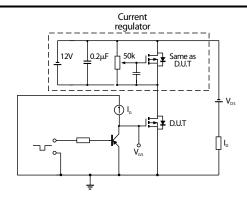


Gate-Source Voltage v Gate Charge

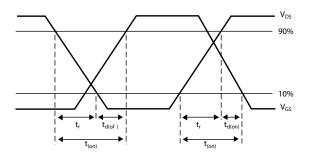
# **Test Circuits**



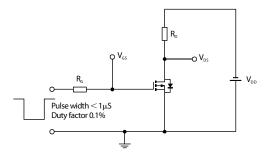
Basic gate charge waveform



Gate charge test circuit



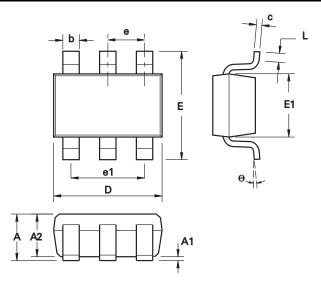
Switching time waveforms



Switching time test circuit

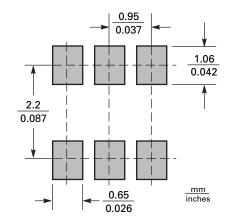


# **Package Outline Dimensions**



DIM	Millin	neters	Inches		
	Min	Max	Min	Max	
Α	0.90	1.45	0.354	0.0570	
A1	0.00	0.15	0.00	0.0059	
A2	0.90	1.30	0.0354	0.0511	
b	0.20	0.20 0.50 0.0078		0.0196	
С	0.09	0.26	0.0035	0.0102	
D	2.70	3.10	0.1062	0.1220	
E	2.20	3.20	0.0866	0.1181	
E1	1.30	1.80	0.0511	0.0708	
L	0.10	0.60	0.0039	0.0236	
е	0.95 REF		0.0374 REF		
e1	1.90 REF		0.0748 REF		
θ	0°	30° 0°		30°	

# **Suggested Pad Layout**







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